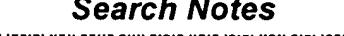


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/642,914	FAN ET AL.
	Examiner	Art Unit
	Charles Kim	2624

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See search history report	1/11/2007	CK
IEEE Search	1/11/2007	CK
Inventor name search	1/11/2007	CK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner